IRPS 2012

IEEE International Reliability Physics Symposium

Monday Tutorial Presentations

April 16, 2012

211: Circuit-level Reliability

221: Advanced Experimental Techniques for BTI Characterization

222: Random Telegraph Noise – Measurement, Analysis, and Consequences

231: Hot Carrier Degradation in High Voltage Devices

232: Reliability of Gallium Nitride High Electron Mobility Transistors

241: Soft Errors in Modern SRAMs

242 : Trap-related Reliability Issues in NAND Flash Memory